**TOSHIBA** 

2SC5322FT

TOSHIBA TRANSISTOR SILICON NPN EPITAXIAL PLANAR TYPE

# 2 S C 5 3 2 2 F T

VHF~UHF BAND LOW NOISE AMPLIFIER APPLICATIONS

Low Noise Figure: NF = 1.4 dB (f = 2 GHz)

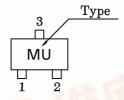
:  $|S_{21e}|^2 = 10 \, dB \, (f = 2 \, GHz)$ High Gain

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT	
Collector-Base Voltage	$V_{\mathrm{CBO}}$	8	V	
Collector-Emitter Voltage	$V_{CEO}$	5	V	
Emitter-Base Voltage	$V_{EBO}$	1.5	V	
Collector Current	$I_{\mathbf{C}}$	10	mA	
Base Current	$I_{\mathrm{B}}$	5	mA	
Collector Power Dissipation	$P_{\mathbf{C}}$	100	mW	
Junction Temperature	$T_{ m j}$	125	°C	
Storage Temperature Range	$\mathrm{T_{stg}}$	-55~125	$^{\circ}\mathrm{C}$	

#### **MARKING**

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## Unit in mm $\pm 0.05$ $1.2 \pm 0.05$ $0.8 \pm 0.05$ $0.32 \pm 0.05$ $14 \pm 0.05$ BASE **EMITTER** 2 TESM COLLECTOR **JEDEC EIAJ TOSHIBA** 2-1B1A

### MICROWAVE CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Transition Frequency	$ m f_{T}$	$V_{CE} = 3 \text{ V}, I_{C} = 7 \text{ mA}$	9		-C.C	GHz
I Incortion (Loin	$ S_{21e} ^2$ (1)	$V_{CE} = 3 V$ , $I_{C} = 7 mA$ , $f = 1 GHz$	12.5	15.5		dB
	$ S_{21e} ^2$ (2)	$V_{CE} = 3 V$ , $I_{C} = 7 mA$ , $f = 2 GHz$	7	10	_	
Noise Figure —	NF (1)	$V_{CE} = 3 V$ , $I_{C} = 3 mA$ , $f = 1 GHz$	_	0.9	1.8	dB
	NF (2)	$V_{CE} = 3 \text{ V}, I_{C} = 3 \text{ mA}, f = 2 \text{ GHz}$	_	1.4	2.2	

### ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cut-off Current	ICBO	$V_{CB} = 8 \text{ V}, I_{E} = 0$	_		1	$\mu$ A
Emitter Cut-off Current	IEBO	$V_{EB} = 1 V, I_{C} = 0$	115		1_	$\mu$ A
DC Current Gain	$h_{ ext{FE}}$	$V_{CE} = 3 V, I_{C} = 7 mA$	50	- TO 1	250	<u> </u>
Output Capacitance	$C_{ob}$	$V_{CB} = 2.5 \text{ V}, I_{E} = 0,$	- +1 Y	0.4	_	pF
Reverse Transfer Capacitance	$\mathrm{C_{re}}$	f = 1 MHz (Note)	_	0.3	0.7	рF

(Note) Cre is measured by 3 terminal method with Capacitance bridge. **CAUTION** 

This device electrostatic sensitivity. Please handle with caution.

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